

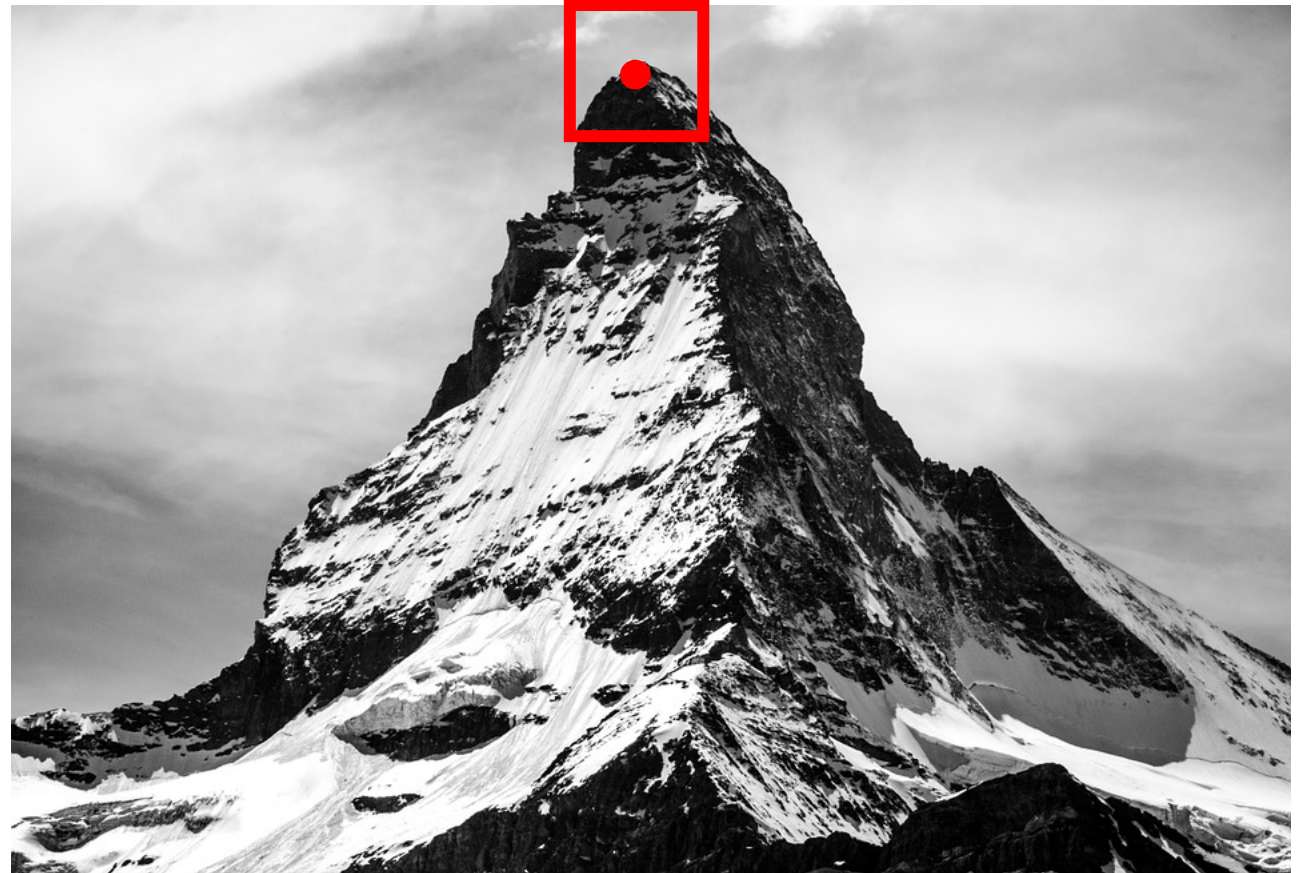
# Feature descriptors and matching

# Feature detection and description

- Harris corner detection gives:
  - Location of each detected corner
  - Orientation of the corner (given by  $\mathbf{x}_{\max}$ )
  - Scale of the corner (the image scale which gives the maximum response at this location)
- Want feature descriptor that is
  - Invariant to photometric transformations, translation, rotation, scaling
  - Discriminative
- P

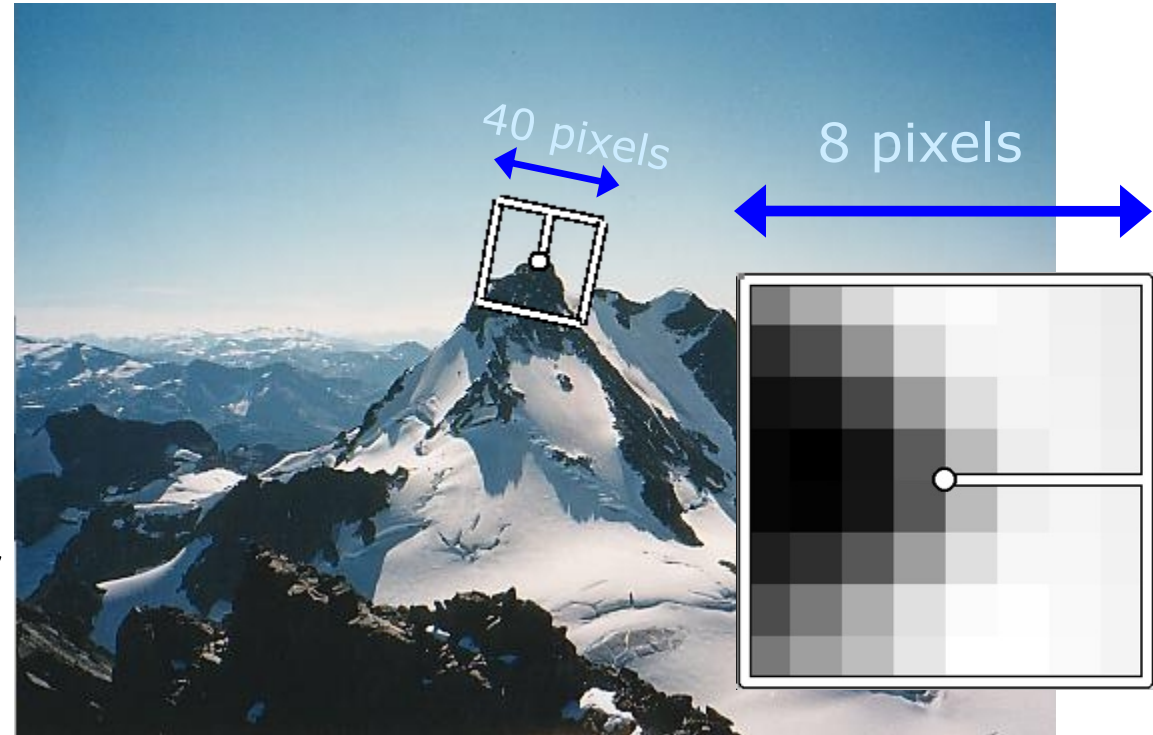
# Multiscale Oriented PatcheS descriptor

- Describe a corner by the patch around that pixel
- Scale invariance by using scale identified by corner detector
- Rotation invariance by using orientation identified by corner detector
- Photometric invariance by subtracting mean and dividing by standard deviation

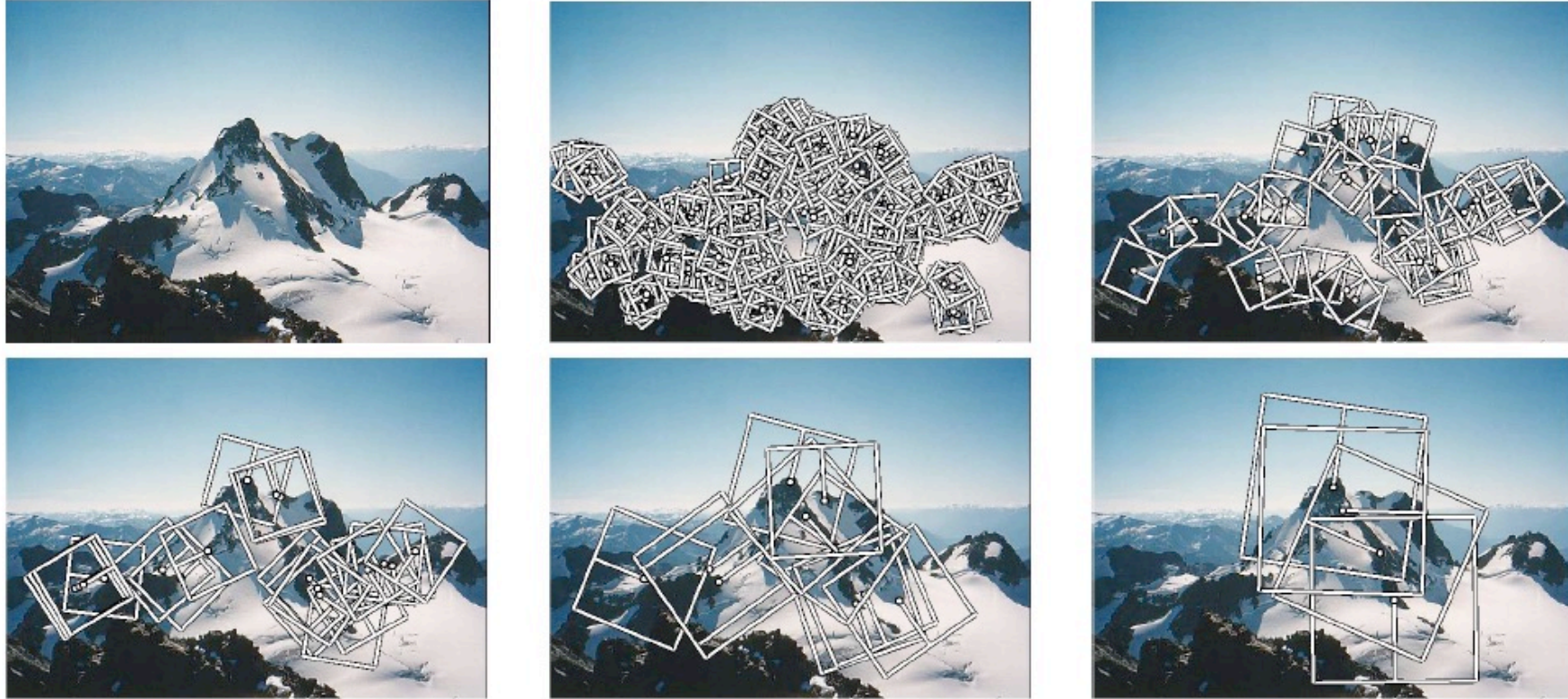


# Multiscale Oriented PatcheS descriptor

- Take 40x40 square window around detected feature at the right scale
- Scale to 1/5 size (using prefiltering)
- Rotate to horizontal
- Sample 8x8 square window centered at feature
- Intensity normalize the window by subtracting the mean, dividing by the standard deviation in the window



# MOPS



*Figure 1. Multi-scale Oriented Patches (MOPS) extracted at five pyramid levels from one of the Matier images. The boxes show the feature orientation and the region from which the descriptor vector is sampled.*

# Detour: Image transformations

- What does it mean to rotate a patch?
- Each pixel has coordinates  $(x,y)$
- Rotation represented by a matrix  $R$
- Pixel's new coordinates:

$$\begin{bmatrix} x' \\ y' \end{bmatrix} = R \begin{bmatrix} x \\ y \end{bmatrix}$$

- $I'(x',y') = I(x,y)$

# Detour: Image transformations

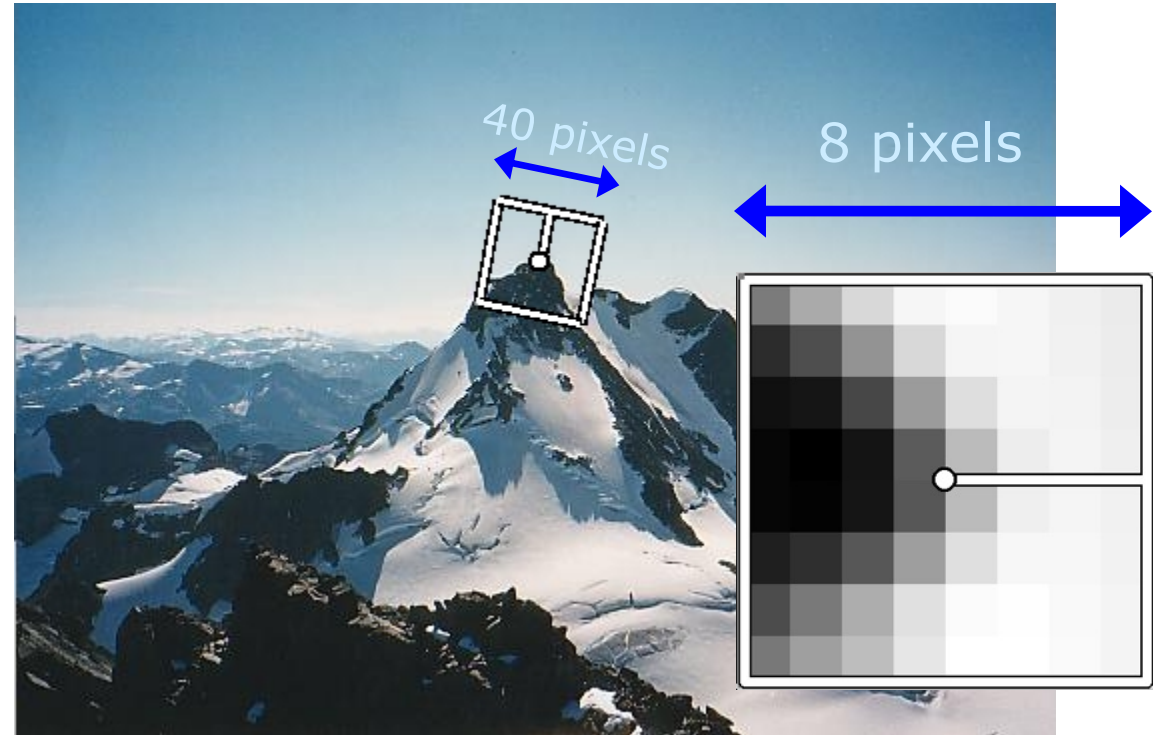
- What if destination pixel is fractional?
- Flip computation: for every destination pixel figure out source pixel
  - Use interpolation if source location is fractional

- $I'(x', y') = I(x, y)$  
$$\begin{bmatrix} x \\ y \end{bmatrix} = R^{-1} \begin{bmatrix} x' \\ y' \end{bmatrix}$$

# Multiscale Oriented PatcheS descriptor

Take 40x40 square window  
around detected feature

- Scale to 1/5 size (using prefiltering)
- Rotate to horizontal
- Sample 8x8 square window centered at feature
- Intensity normalize the window by subtracting the mean, dividing by the standard deviation in the window





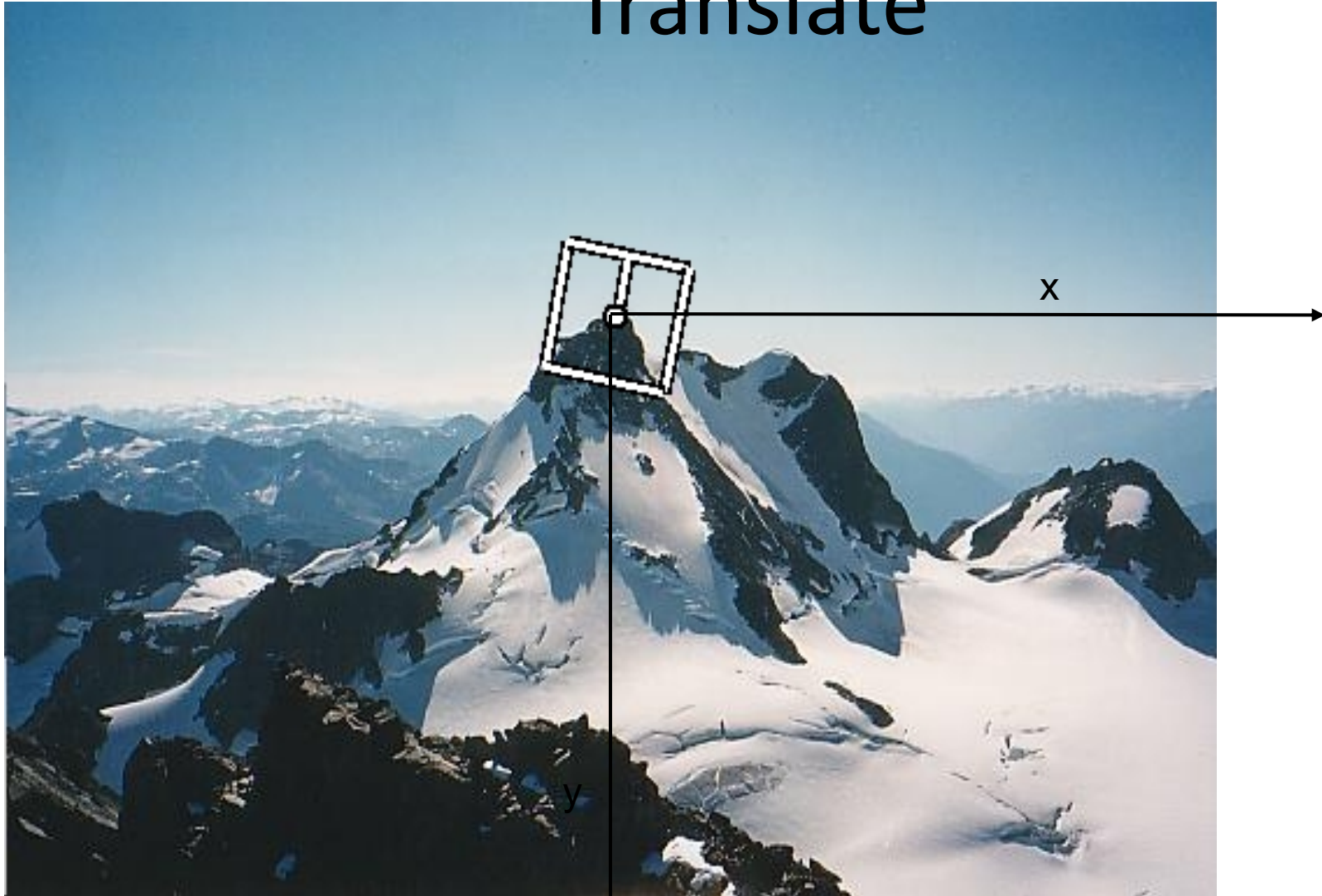
# MOPS descriptor

- You can combine transformations together to get the final transformation

$T = ?$

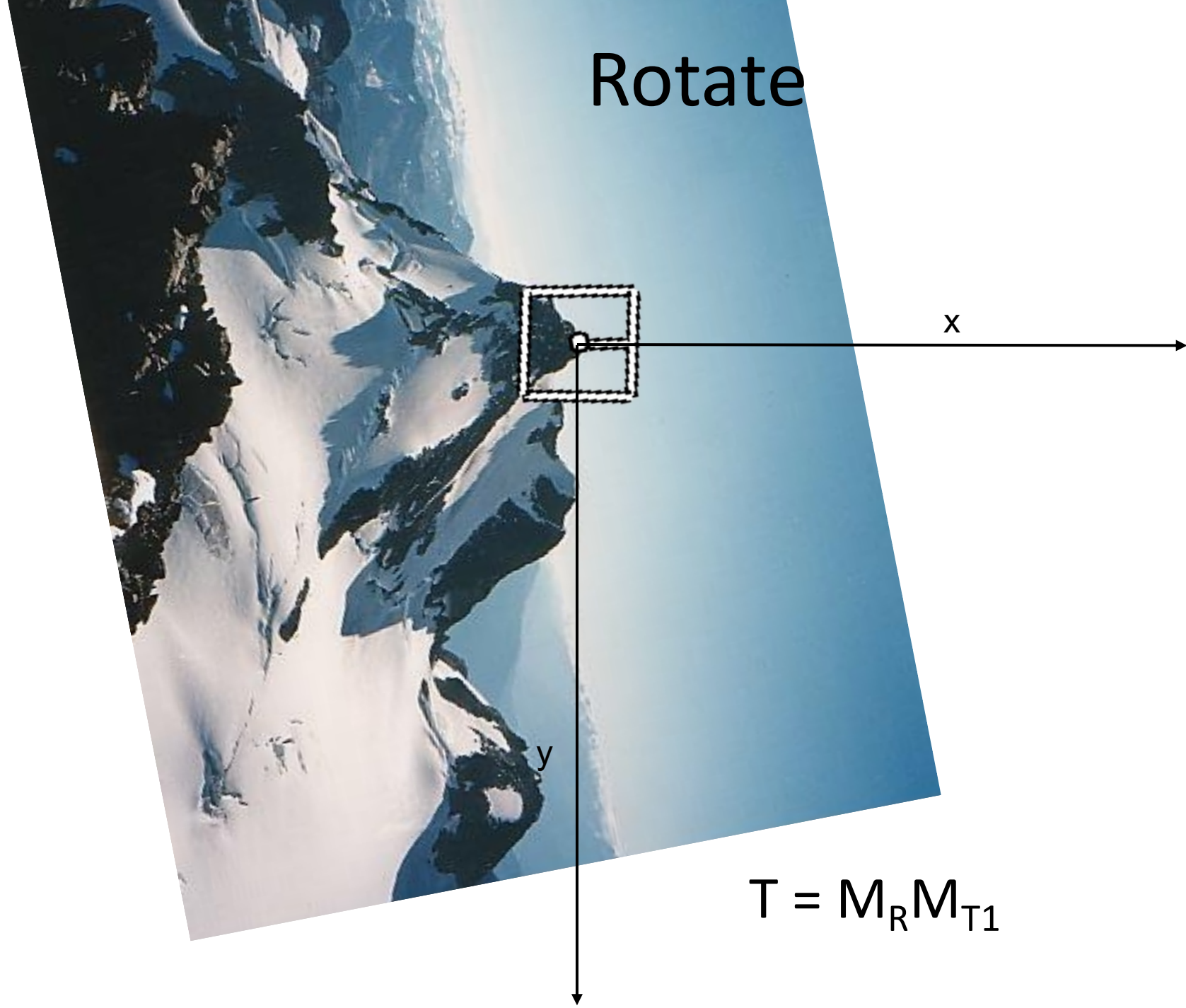


# Translate



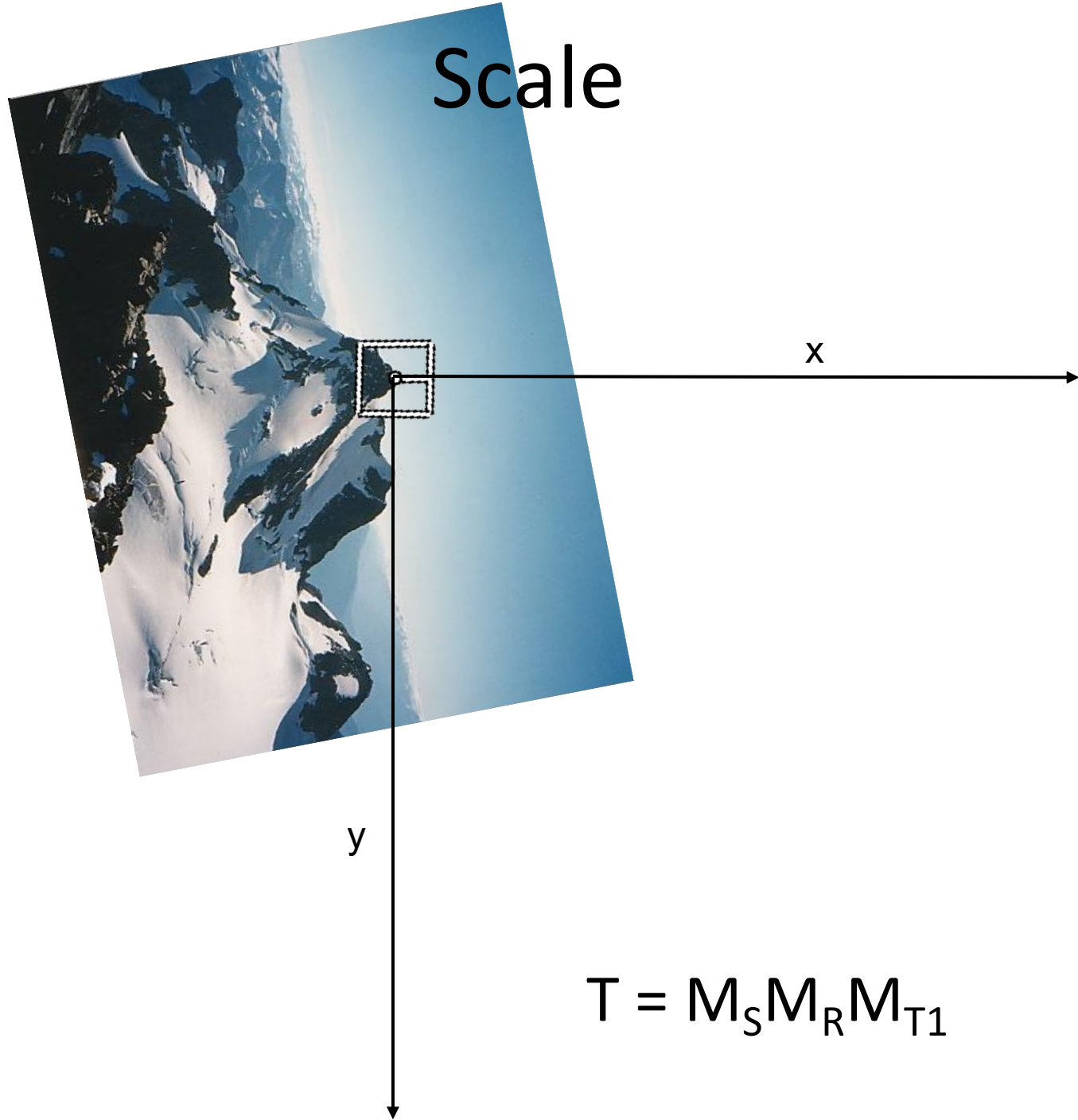
$$T = M_{T1}$$

Rotate



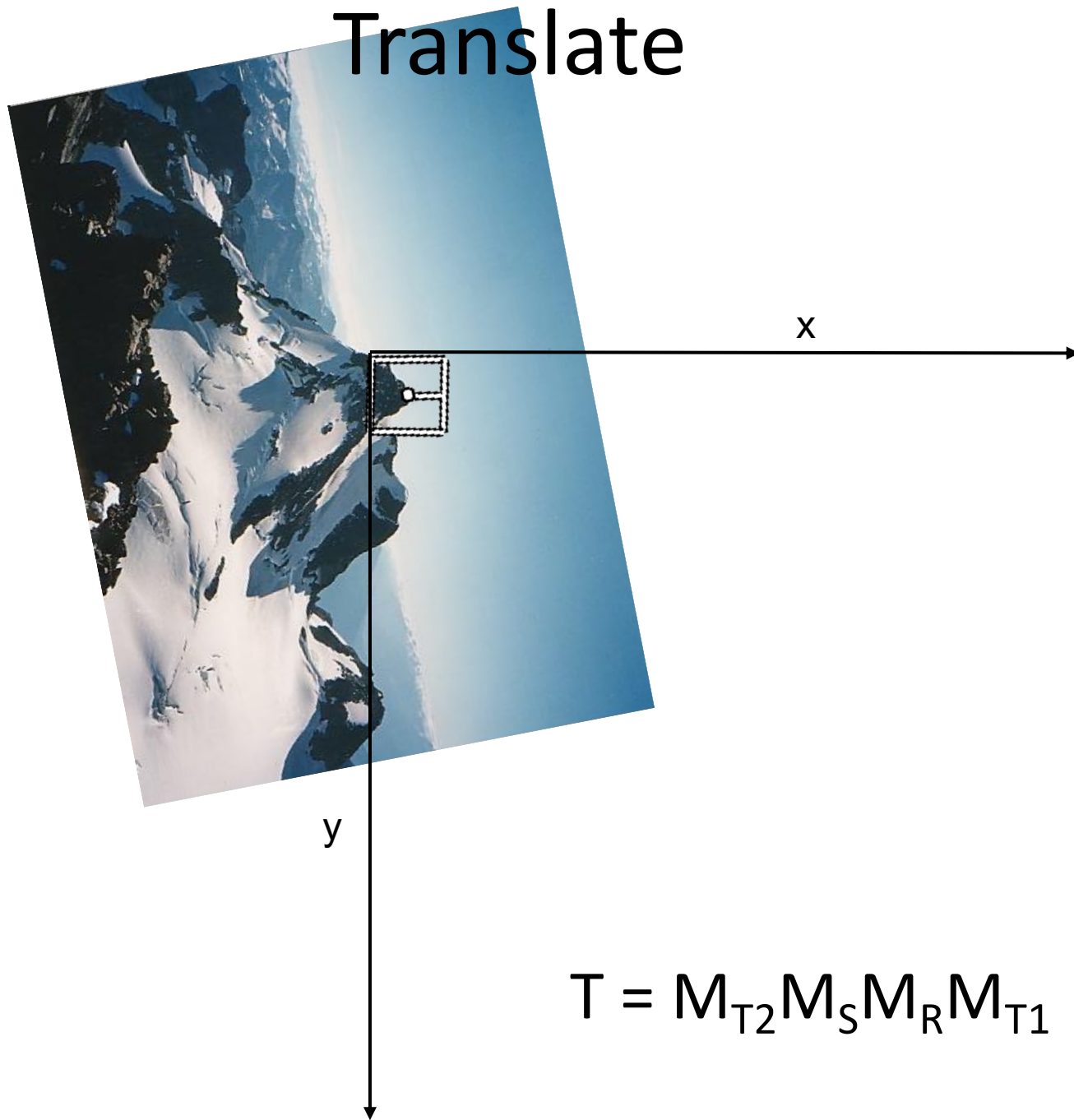
$$T = M_R M_{T1}$$

# Scale

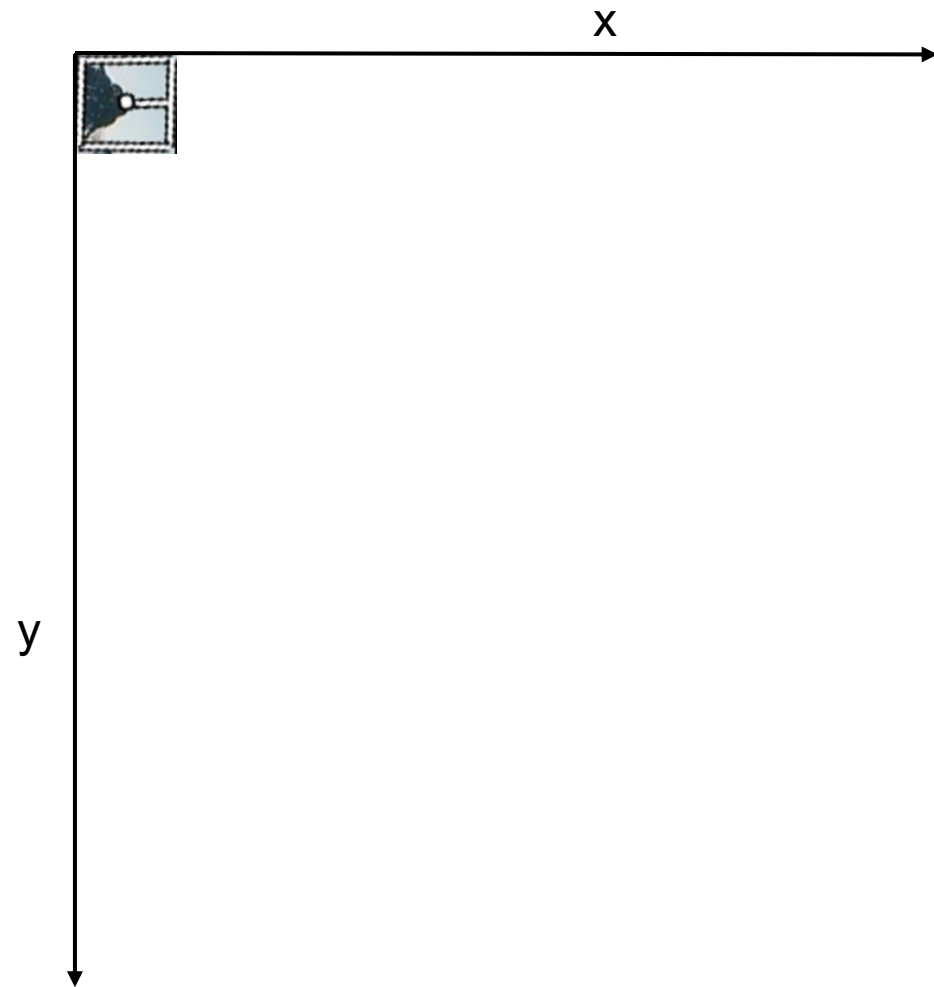


$$T = M_S M_R M_{T1}$$

# Translate



# Crop

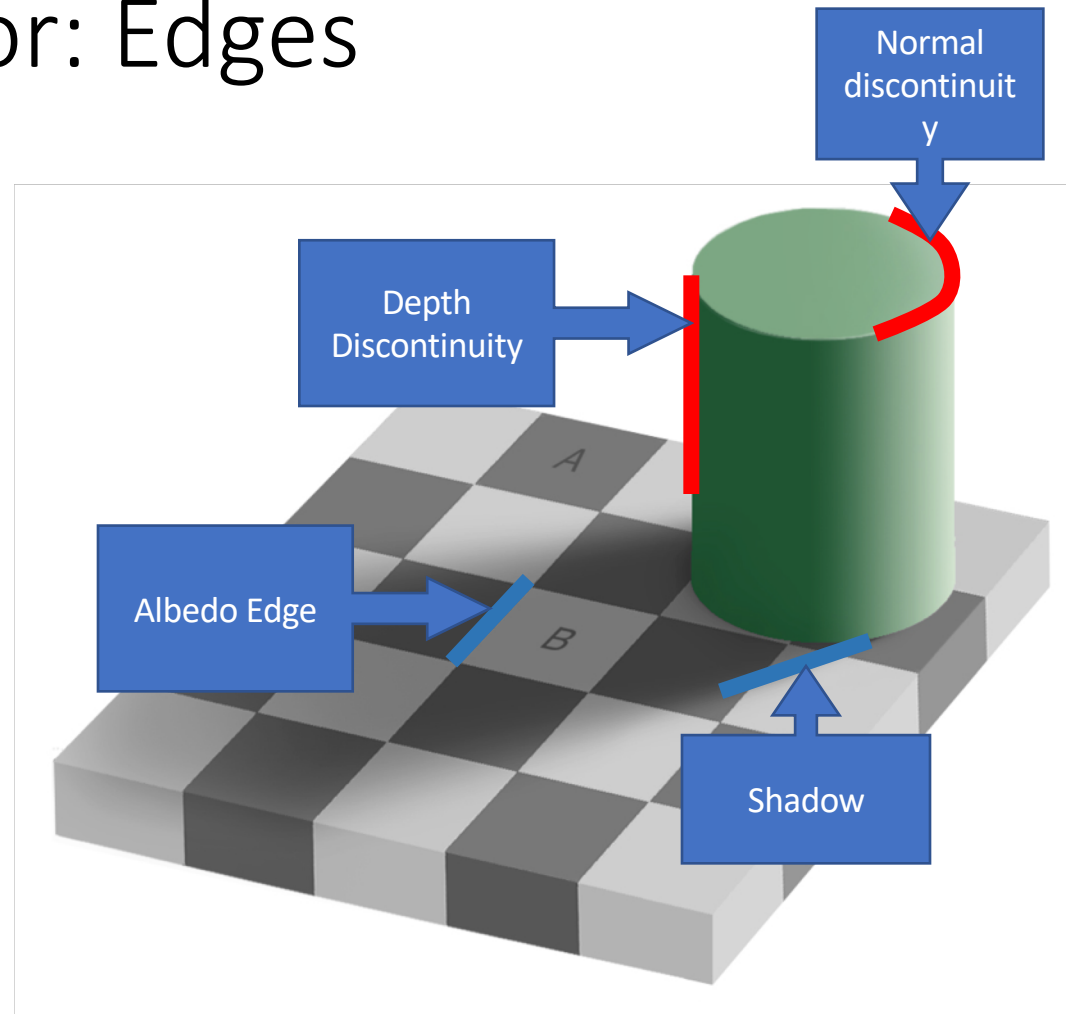


# Color and Lighting

- Have invariance to additive and multiplicative changes to intensity
- But what about more sophisticated changes to intensity?



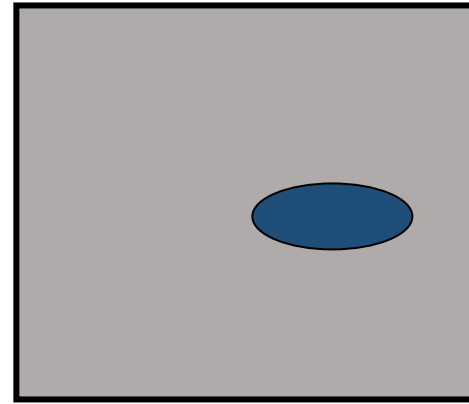
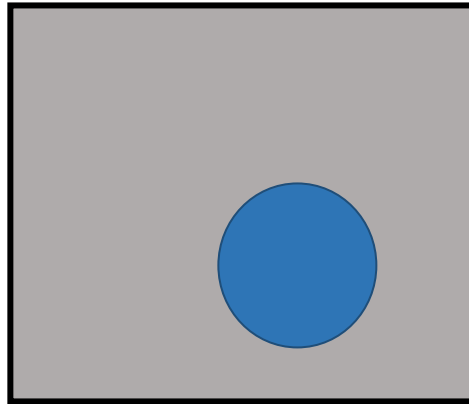
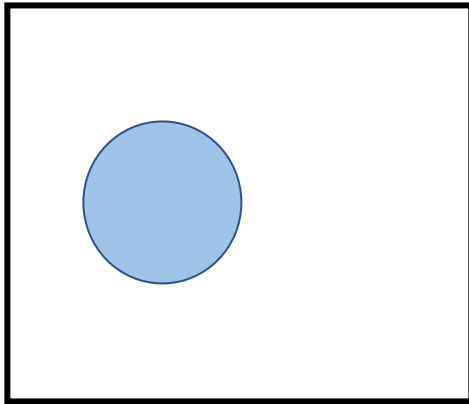
# Better representation than color: Edges





# Out-of-plane rotation

- Invariant to translation and rotation
- But what about more sophisticated geometric transformations



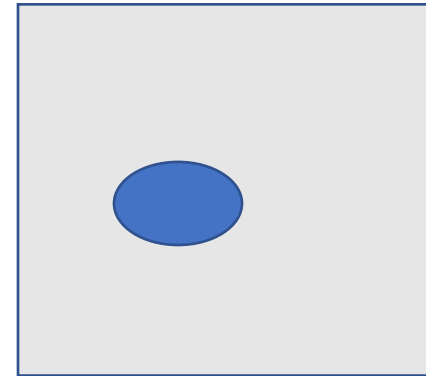
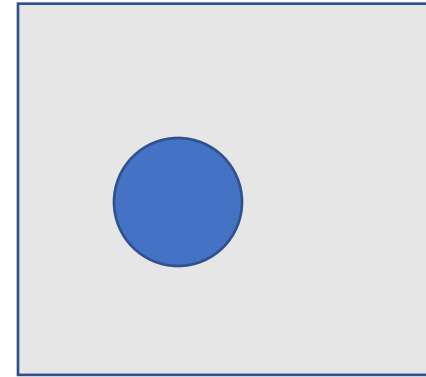
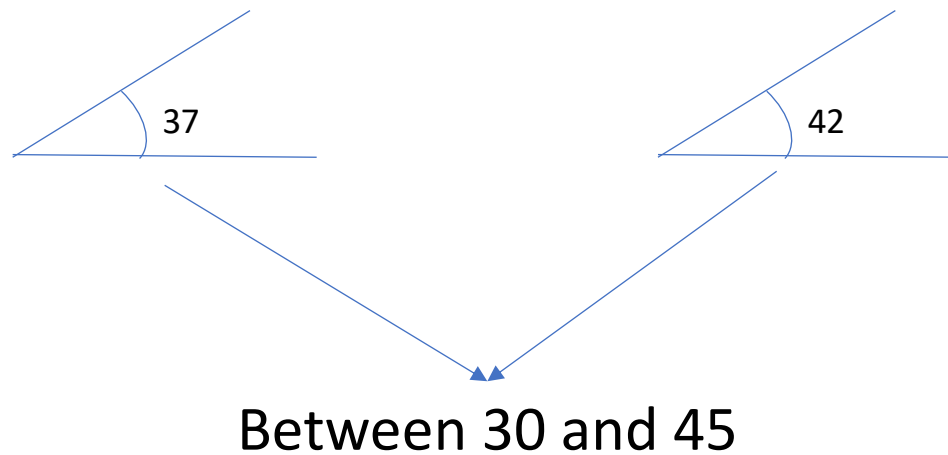
Out-of-plane rotation

# Towards a better feature descriptor

- Match *pattern of edges*
  - Edge orientation – clue to shape
  - Invariant to almost all photometric transformations
- Be resilient to *small deformations*
  - Deformations might move pixels around, but slightly
  - Deformations might change edge orientations, but slightly

# Invariance to deformation

- Precise edge orientations are not resilient to out-of-plane rotations and deformations
- But we can *quantize* edge orientation: only record rough orientation

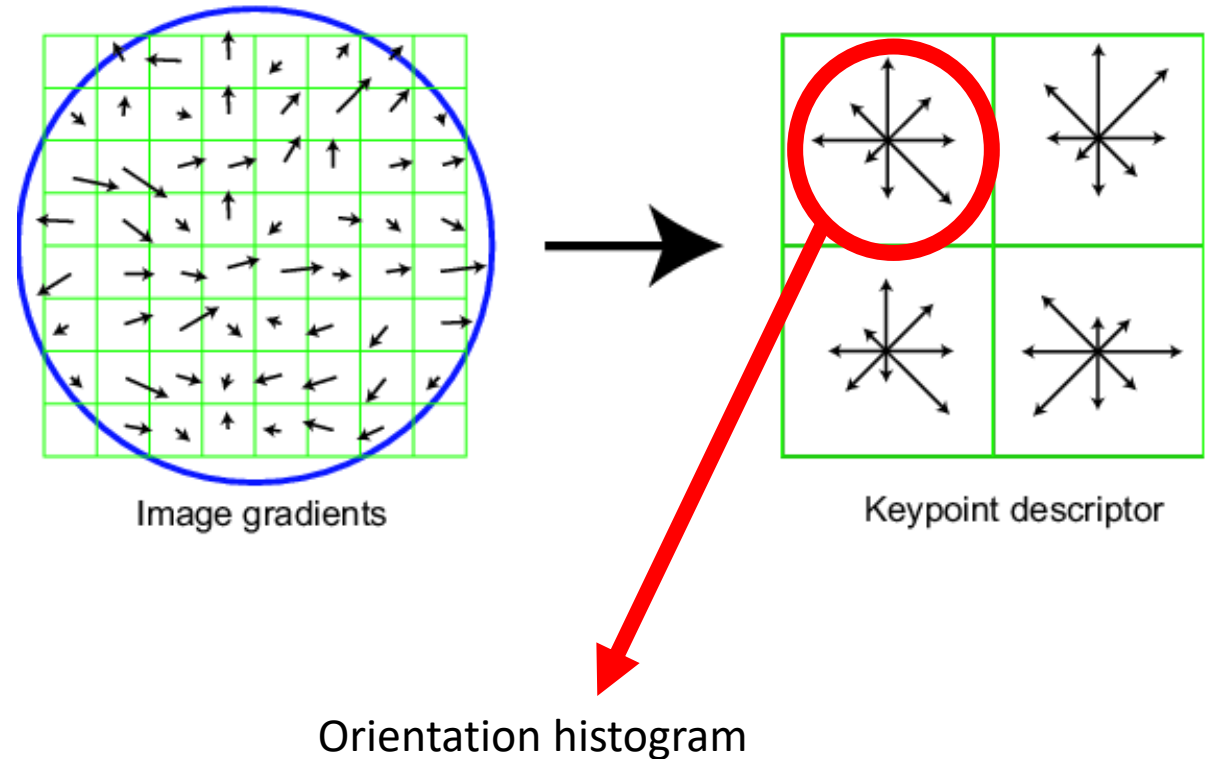


# Invariance to deformation

$$g(\theta) = \begin{cases} 0 & \text{if } 0 < \theta < 2\pi/N \\ 1 & \text{if } 2\pi/N < \theta < 4\pi/N \\ 2 & \text{if } 4\pi/N < \theta < 6\pi/N \\ \dots & \dots \\ N - 1 & \text{if } 2(N - 1)\pi/N < \theta < 2N\pi/N \end{cases}$$

# Invariance to deformation

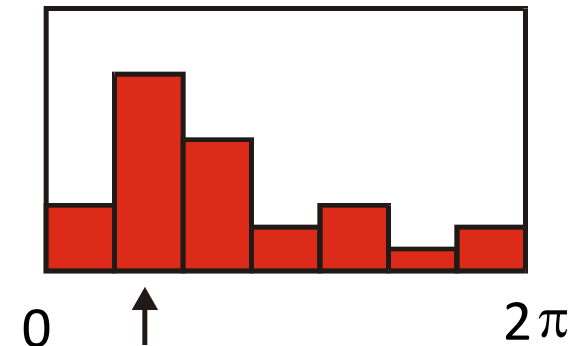
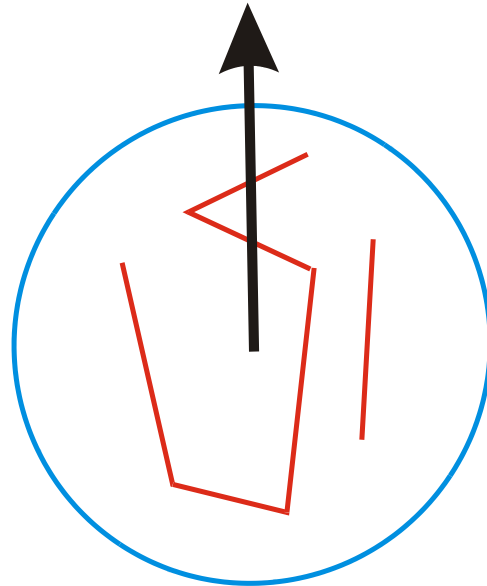
- Deformation can also move pixels around
- Again, instead of precise location of each pixel, only want to record rough location
- Divide patch into a grid of *cells*
- Record *counts* of each orientation in each cell: *orientation histograms*



# Rotation Invariance by Orientation Normalization

[Lowe, SIFT, 1999]

- Compute orientation histogram
- Select dominant orientation (mode of the histogram; alternative to eigenvector of second moment matrix)
- Normalize: rotate to fixed orientation



# The SIFT descriptor

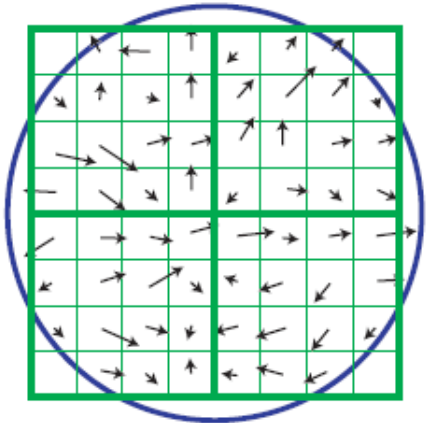
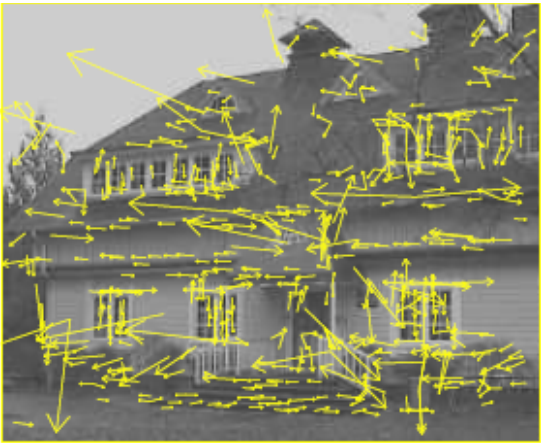
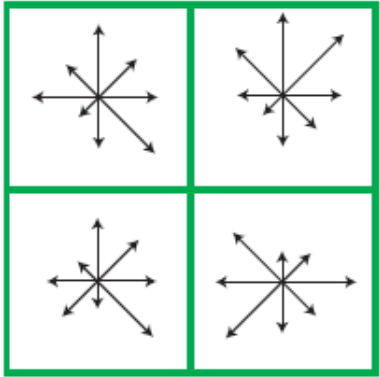


Image gradients



Keypoint descriptor

SIFT – Lowe IJCV 2004

# Scale Invariant Feature Transform

Basic idea:

- DoG for scale-space feature detection
- Take 16x16 square window around detected feature
  - Compute gradient orientation for each pixel
  - Throw out weak edges (threshold gradient magnitude)
  - Create histogram of surviving e

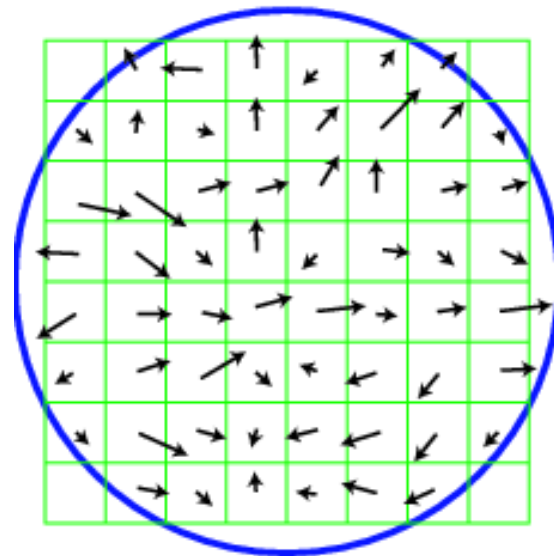
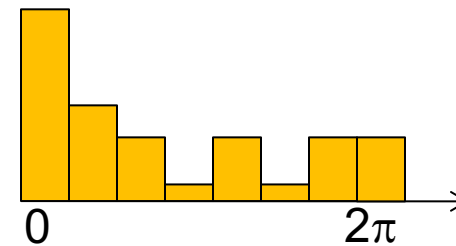
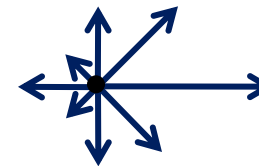


Image gradients



angle histogram



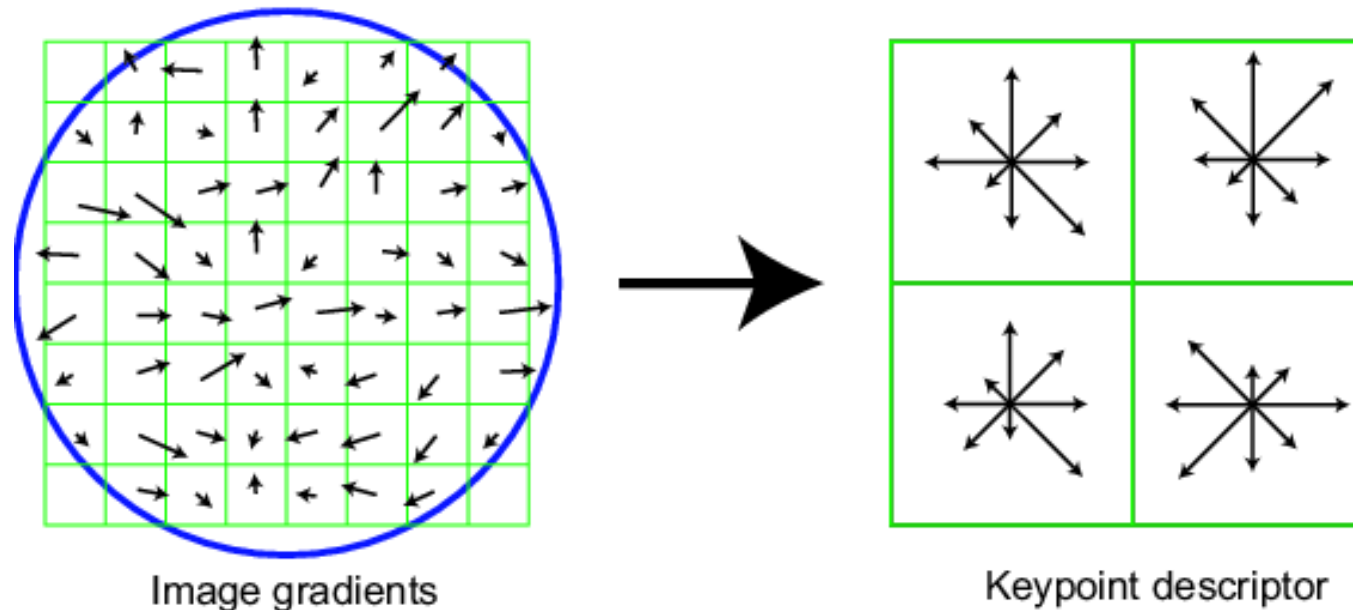
Keypoint descriptor



# SIFT descriptor

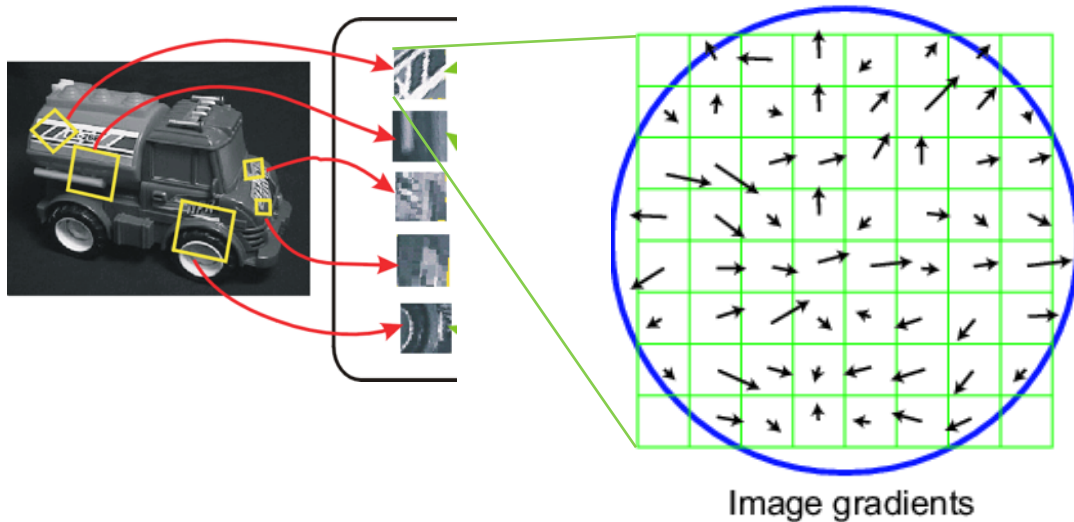
Create histogram

- Divide the 16x16 window into a 4x4 grid of cells (2x2 case shown below)
- Compute an orientation histogram for each cell
- 16 cells \* 8 orientations = 128 dimensional descriptor



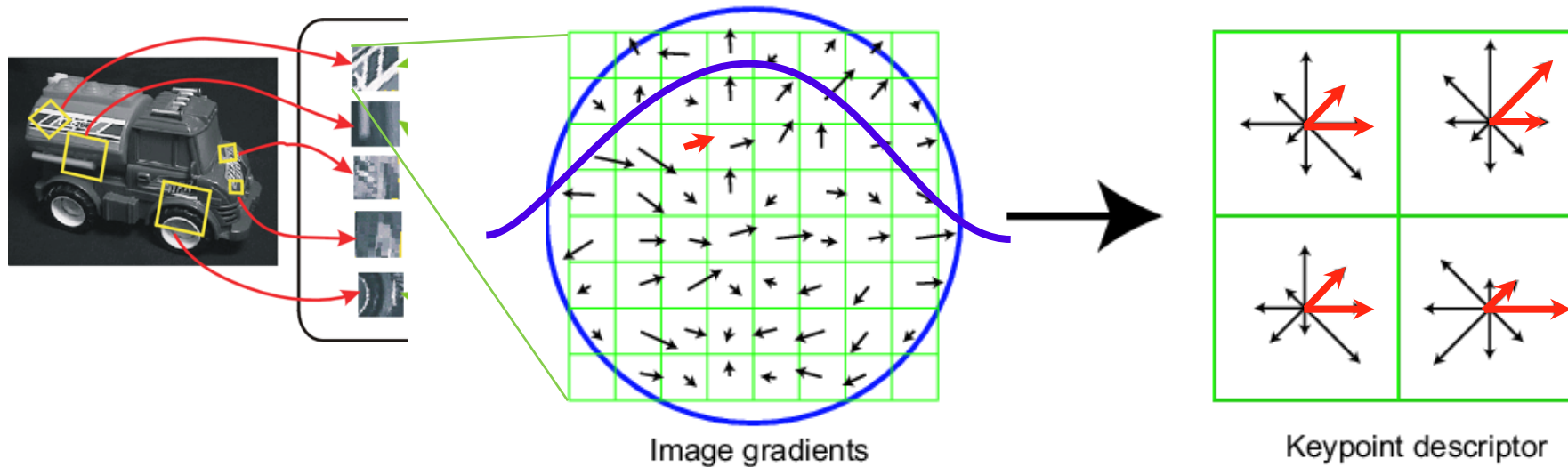
# SIFT vector formation

- Computed on rotated and scaled version of window according to computed orientation & scale
  - resample the window
- Based on gradients weighted by a Gaussian



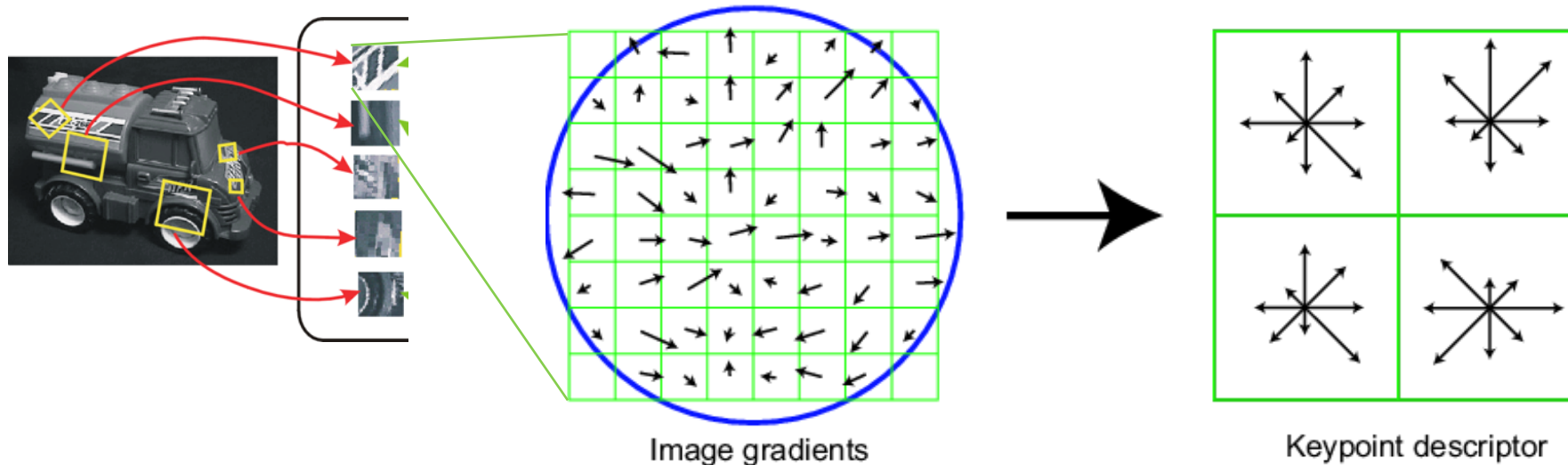
# Ensure smoothness

- Trilinear interpolation
  - a given gradient contributes to 8 bins:  
4 in space times 2 in orientation



# Reduce effect of illumination

- 128-dim vector normalized to 1
- Threshold gradient magnitudes to avoid excessive influence of high gradients
  - after normalization, clamp gradients  $>0.2$
  - renormalize



# Properties of SIFT

## Extraordinarily robust matching technique

- Can handle changes in viewpoint
  - Up to about 60 degree out of plane rotation
- Can handle significant changes in illumination
  - Sometimes even day vs. night (below)
- Fast and efficient—can run in real time
- Lots of code available:  
[http://people.csail.mit.edu/albert/ladypack/wiki/index.php/Known\\_implementations\\_of\\_SIFT](http://people.csail.mit.edu/albert/ladypack/wiki/index.php/Known_implementations_of_SIFT)



# Summary

- Keypoint detection: repeatable and distinctive
  - Corners, blobs, stable regions
  - Harris, DoG
- Descriptors: robust and selective
  - spatial histograms of orientation
  - SIFT and variants are typically good for stitching and recognition
  - But, need not stick to one

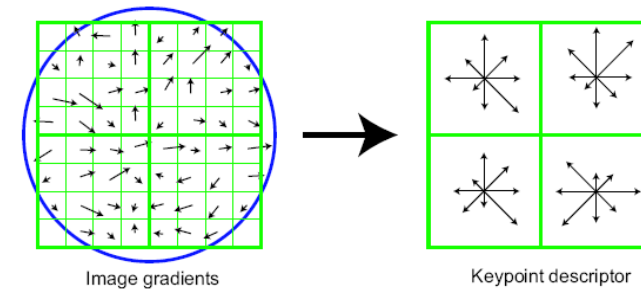
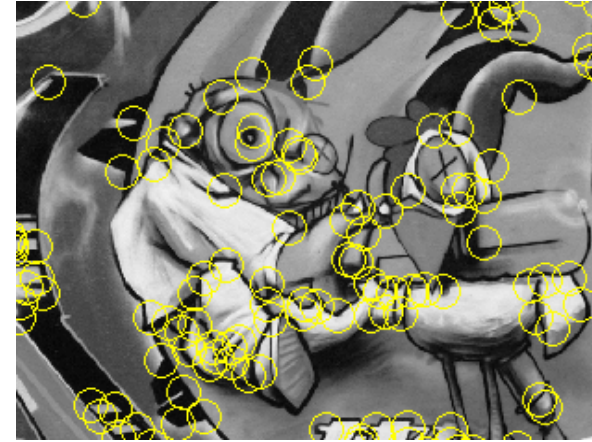
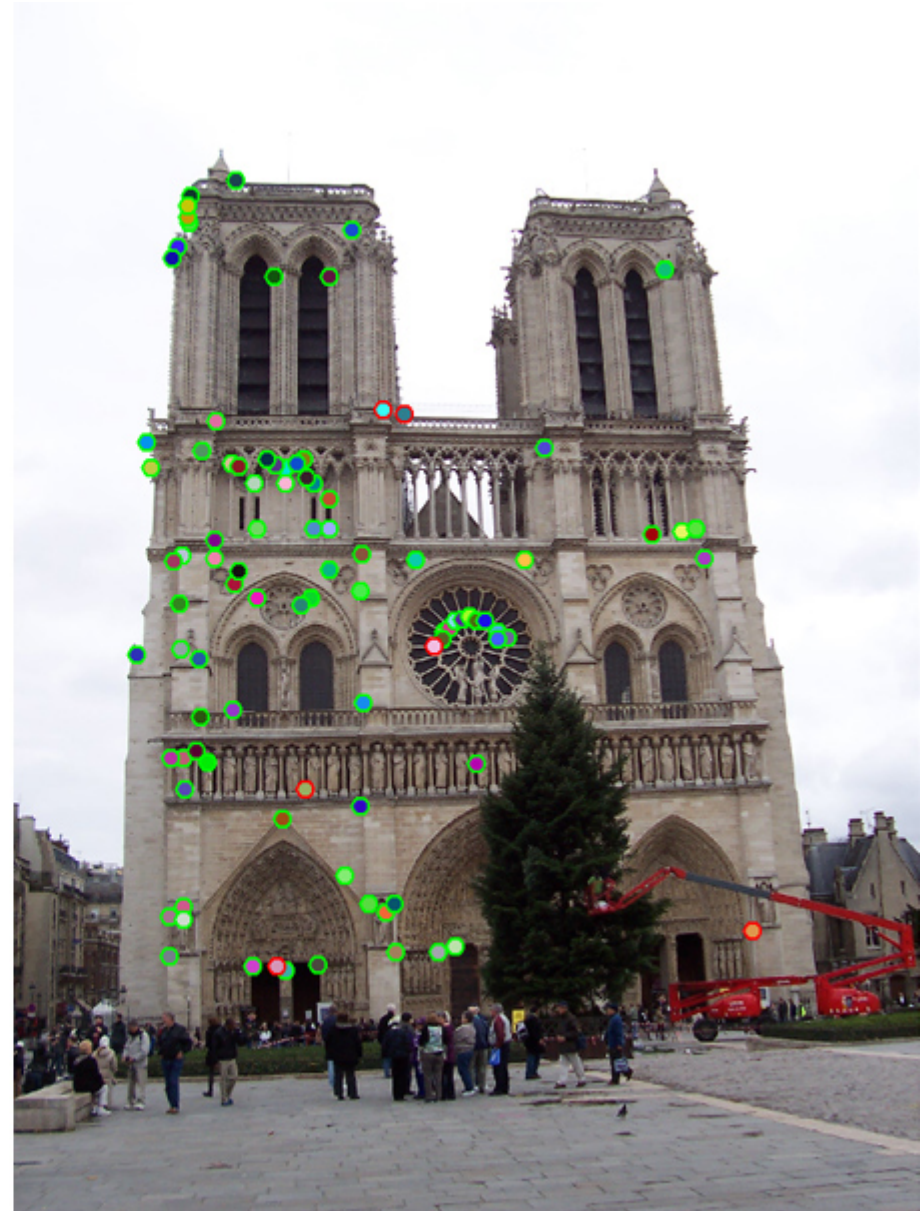
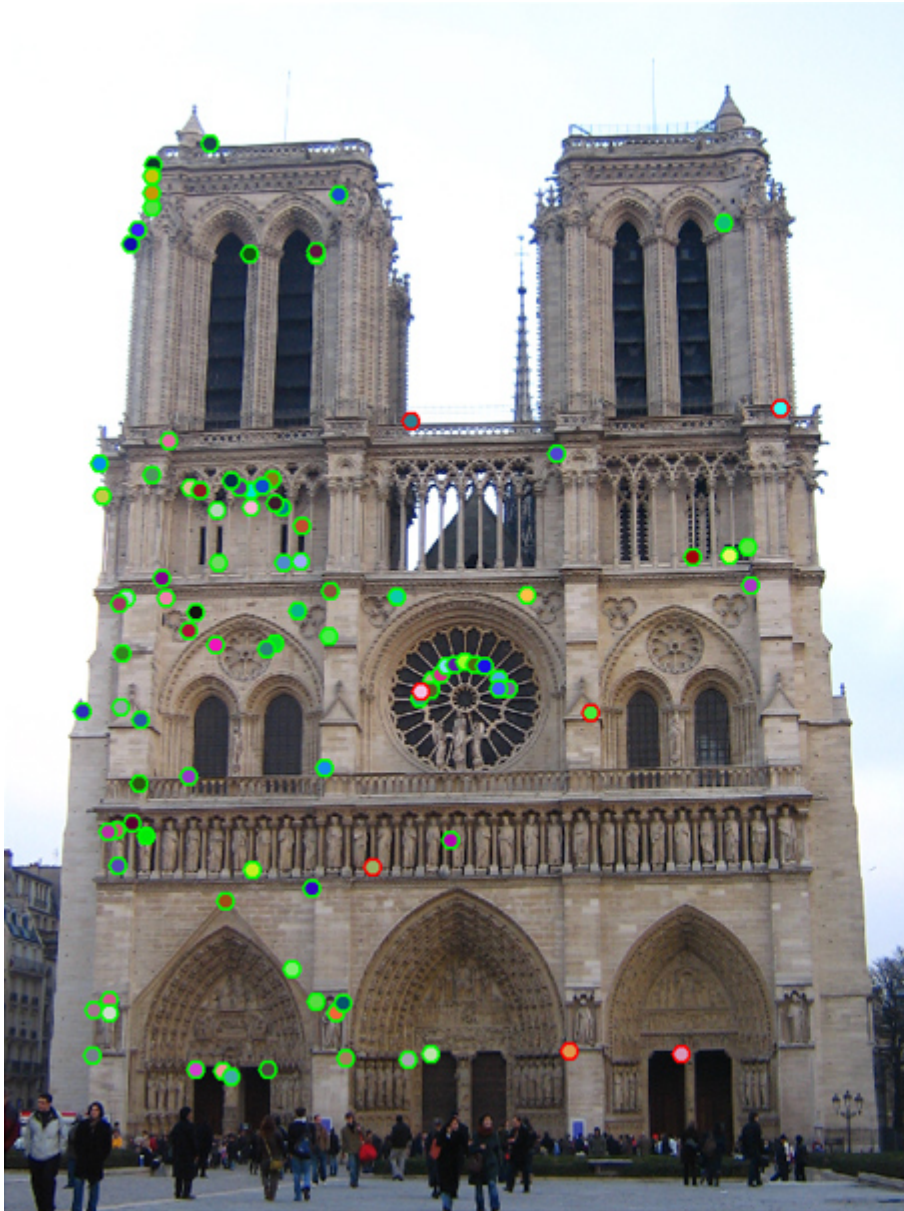


Image gradients

Keypoint descriptor

# Which features match?



# Feature matching

Given a feature in  $I_1$ , how to find the best match in  $I_2$ ?

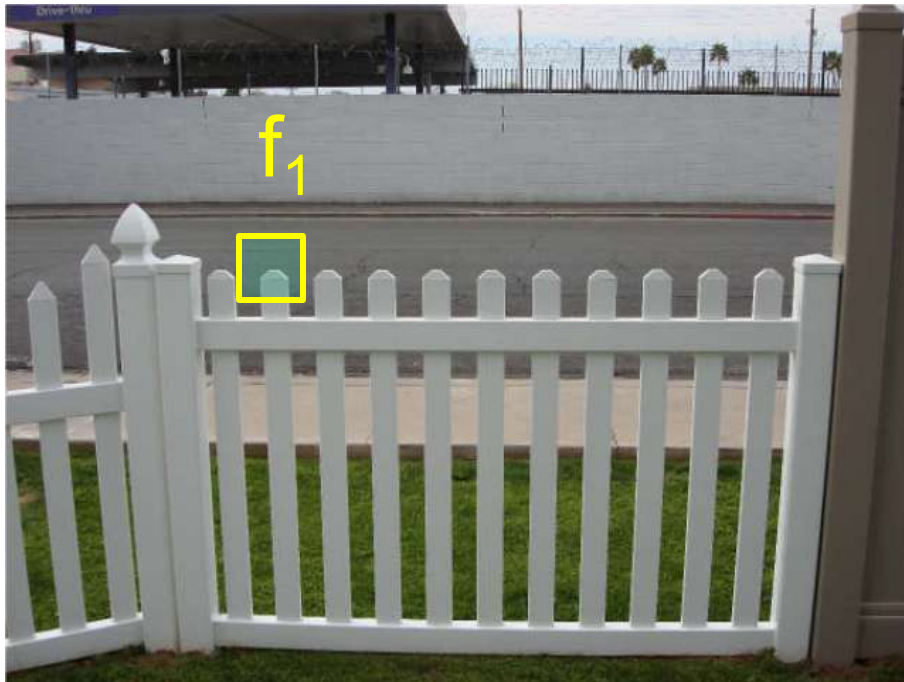
1. Define distance function that compares two descriptors
2. Test all the features in  $I_2$ , find the one with min distance



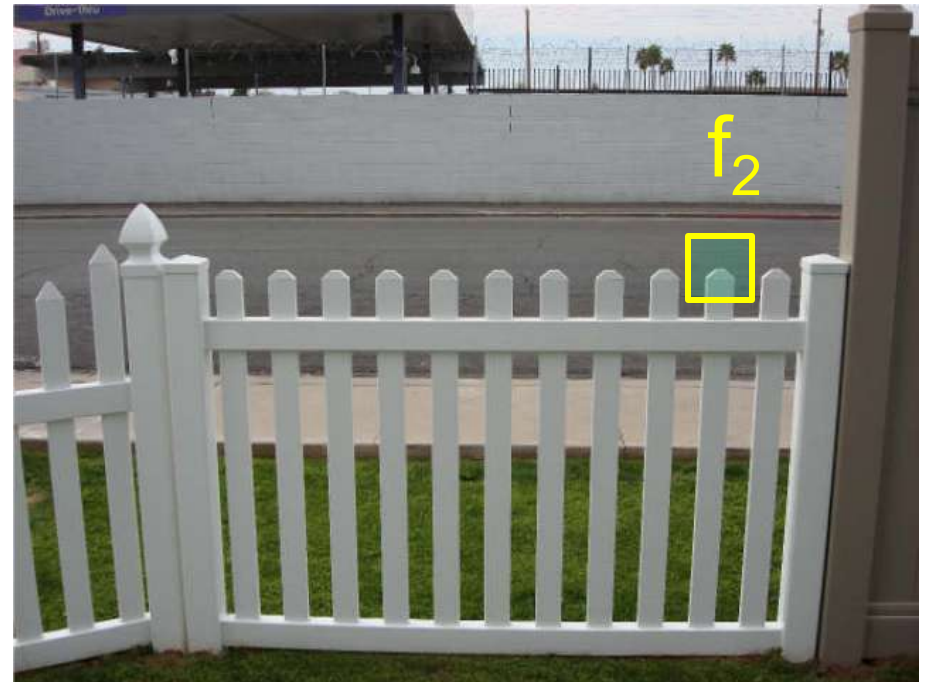
# Feature distance

How to define the difference between two features  $f_1, f_2$ ?

- Simple approach:  $L_2$  distance,  $\|f_1 - f_2\|$
- can give good scores to ambiguous (incorrect) matches



$I_1$

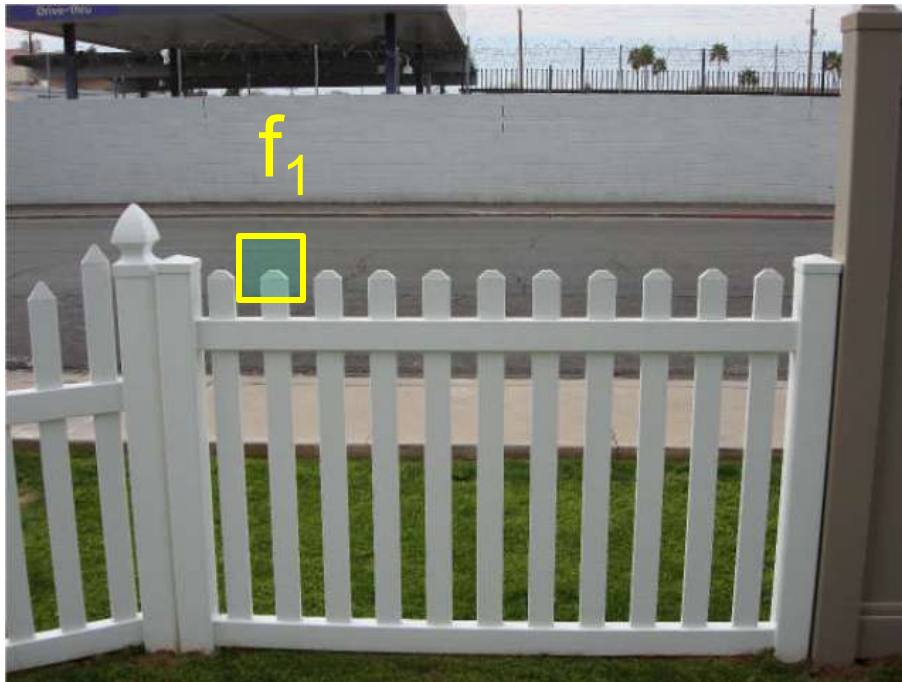


$I_2$

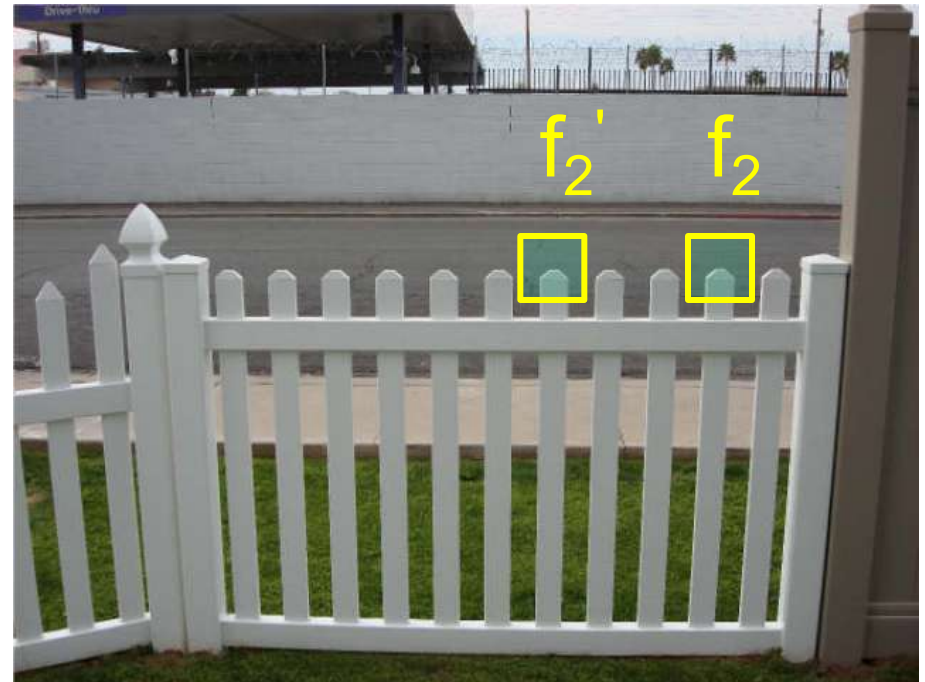
# Feature distance

How to define the difference between two features  $f_1, f_2$ ?

- Better approach: ratio distance =  $\|f_1 - f_2\| / \|f_1 - f_2'\|$ 
  - $f_2$  is best SSD match to  $f_1$  in  $I_2$
  - $f_2'$  is 2<sup>nd</sup> best SSD match to  $f_1$  in  $I_2$
  - gives large values for ambiguous matches



$I_1$



$I_2$